Search Notes



| Application/Control N | Ο. |
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Applicant(s)/Patent Under Reexamination

VAINIO ET AL.

Examiner

MARCOS BATISTA

Art Unit

2617

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-------------|-----------|----------|
| 455 | 209 | 3/11/2008 | mb |
| 370 | 286 | 3/11/2008 | mb |
| 348 | 14.01-14.14 | 3/11/2009 | mb |
| 455 | all | 3/11/2009 | mb |
| 370 | all | 8/26/2009 | mb |

SEARCH NOTES

| Search Notes | Date | Examiner |
|---------------------------------------|------------|----------|
| Consulted with Steve D'Aghosta | 3/11/2008 | mb |
| Consulted w/ lab TA Yogesh Aggarwal | 3/11/2008 | mb |
| Consulted with Lun-Yi Lao | 3/11/2008 | mb |
| Inventor's Name Search | 10/22/2008 | mb |
| East Search | 10/22/2008 | mb |
| Consulted with Rafael Perez Gutierrez | 2/8/2010 | mb |

INTERFERENCE SEARCH

| Class | Subclass | Date | Examiner | |
|-------|----------|----------|----------|--|
| 455 | all | 2/8/2010 | /M.B./ | |
| 370 | all | 2/8/2010 | /M.B./ | |

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